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APPLICATION NO. FILING DATE		FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/609,387	07/03/2000	T. Frank Wang	8229-006-27	3989	
7:	90 03/13/2003				
Steven B Kelber Piper Marbury Rudnick & Wolfe LLP			EXAMINER		
1200 Nineteenth Street NW			PEREZ RAMOS, VANESSA		
Washington, DC 20036-2412			ART UNIT	PAPER NUMBER	
			1765		
		DATE MAILED: 03/13/2003			

Please find below and/or attached an Office communication concerning this application or proceeding.

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.	_	Application N	0.	Applicant(s)	7
	Office Action Summary	09/609,387		WANG, T. FRANK	
	Onice Action Summary	Examiner		Art Unit	·
	The MAN INC DATE AND	Vanessa Pere	z-Ramos	1765	
Period fo	The MAILING DATE of this communication apor Reply	ppears on the cov	er sheet with the c	orrespondence addre	ss
- Exte after - if the - If NC - Failu - Any	MAILING DATE OF THIS COMMUNICATION mislons of time may be available under the provisions of 37 CFR 1. SIX (6) MONTHS from the mailing date of this communication. It is period for reply specified above is less than thirty (30) days, a regular period for reply is specified above, the maximum statutory period increase of the period for reply within the set or extended period for reply will, by statustreply received by the Office later than three months after the mailing and patent term adjustment. See 37 CFR 1.704(b).	136(a). In no event, ho oly within the statutory n I will apply and will expi	wever, may a reply be tim ninimum of thirty (30) days e SIX (6) MONTHS from t	ely filed will be considered timely. the mailing date of this commu	unication.
1) 🖂	Responsive to communication(s) filed on 12	(16/02			
2a) ☐			E 1		
3)	/	his action is non-			
,	Since this application is in condition for allow closed in accordance with the practice under on of Claims	rance except for Ex parte Quayle	formal matters, pro e, 1935 C.D. 11, 49	osecution as to the m 53 O.G. 213.	erits is
4) 🔯	Claim(s) 1-35 is/are pending in the applicatio	n.			
	4a) Of the above claim(s) is/are withdra		ration.		
	Claim(s) is/are allowed.				
6)⊠	Claim(s) 1-35 is/are rejected.				
	Claim(s) is/are objected to.				
	Claim(s) are subject to restriction and/o	or election require	ement		
Application	on Papers				
9)∐ Т	The specification is objected to by the Examine	er.			
10)∐ T	he drawing(s) filed on is/are: a)∏ acce	pted or b)⊡ objec	ted to by the Exam	iner.	
	Applicant may not request that any objection to the	e drawing(s) be he	ld in abeyance. See	∋ 37 CFR 1.85(a).	
11)[_] T	he proposed drawing correction filed on	_ is: a)⊡ approv	ed b)⊡ disapprov	ed by the Examiner.	
40) 🗆 🖚	If approved, corrected drawings are required in re		tion.		
	he oath or declaration is objected to by the Ex	aminer.			
	nder 35 U.S.C. §§ 119 and 120				
13) 🗌 📝	Acknowledgment is made of a claim for foreigr	priority under 3	5 U.S.C. § 119(a)-	(d) or (f).	
a) <u></u>	☐ All b)☐ Some * c)☐ None of:				
1	1.☐ Certified copies of the priority documents	s have been rece	ived.		
2	2. Certified copies of the priority documents	s have been rece	ived in Application	ı No	
	B. Copies of the certified copies of the prior application from the International But	ity documents ha	ive been received	in this National Stage	Э
14)□ Ac	ee the attached detailed Office action for a list of	or the certified co	ppies not received.		
ا (ھ	knowledgment is made of a claim for domestic	priority under 3	o U.S.C. § 119(e)	(to a provisional appli	ication).
15)∐ Ac	☐ The translation of the foreign language procknowledgment is made of a claim for domesti	visional applicati c priority under 3	on nas been receiv 5 U.S.C. && 120 a	/ed. nd/or 121	
Attachment(s	5)	- Priving under U	0 0.0.0. 33 120 a	HM/ULIZI.	
) 🔲 Notice (of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (PTO-948) tion Disclosure Statement(s) (PTO-1449) Paper No(s)	5)	Interview Summary (P Notice of Informal Pate Other:	PTO-413) Paper No(s) ent Application (PTO-152)	
Patent and Trad O-326 (Rev.	04.043	ion Summary		Part of Paner I	No. 11

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DETAILED ACTION

Claim Rejections - 35 USC § 112

1. The following is a quotation of the first paragraph of 35 U.S.C. 112:

The specification shall contain a written description of the invention, and of the manner and process of making and using it, in such full, clear, concise, and exact terms as to enable any person skilled in the art to which it pertains, or with which it is most nearly connected, to make and use the same and shall set forth the best mode contemplated by the inventor of carrying out his invention.

2. Claims 1, 15 and 31 are rejected under 35 U.S.C. 112, first paragraph, as containing subject matter which was not described in the specification in such a way as to reasonably convey to one skilled in the relevant art that the inventor(s), at the time the application was filed, had possession of the claimed invention. In the aforementioned claims, Applicant claims an etchant chemistry which is free of BCL3. However, Applicant's Specification discloses that BCl3 CAN be present in the etchant chemistry, as long as it is not the source of the chlorine. Therefore, the limitation that BCl3 can not be present at all in the etchant chemistry represents new matter.

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claims 1-4, 6 and 9-11are rejected under 35 U.S.C. 103(a) as being unpatentable over Chen et al. (U.S. 5,545,289) in view of Hoh et al. (U.S. 5,874,363).

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In regard to claims 1-4, 6 and 9-11, Chen discloses a method for etching a semiconductor device comprising: providing a device having a plurality of layers, including a layer comprising a refractory metal containing material, including a Ti-W alloy (col. 19, lines 43-46); and etching with a composition comprising a first etchant chemistry which comprises a chlorine source, including Cl2 (col. 19, lines 56-60), and further comprises N2 (col. 19, line 60), and a second etchant which is free of fluorine (col. 20, lines 15-17), and further comprises a chlorine source, including Cl2 (col. 20, line 16).

Contrary to the claimed invention, Chen does not disclose that the etchant chemistry is free of BCI3.

Hoh discloses an etch chemistry with a chlorine source, and discloses that it is preferable that the etchant is free of BCl3, so as to obtain a slower, more controllable rate of material removal, and a low risk of damage (col. 2, lines 60-67 and col. 3, lines 1-6).

It is the Examiner's position that it would have been obvious to one of ordinary skill in the art at the time of the invention to modify Chen by utilizing an etchant chemistry free of BCI3, because this would allow for better etching, more control over the process and lower damage, which are extremely important considerations during semiconductor manufacturing.

5. Claims 5, 7-8 and 12-35 are rejected under 35 U.S.C. 103(a) as being unpatentable over Chen et al. (U.S. 5,545,289) in view of Hoh (U.S. 5,874,363) as applied to claims 1-4, 6 and 9-11 above, and in view of Shoji (U.S. 5,853,602).

In regard to claims 5 and 7, Chen in view of Hoh does not disclose that the first etchant further comprises a fluorine source.

Shoji discloses a method comprising: providing a semiconductor device having a plurality of layers, including a refractory metal containing layer and an oxide layer, and etching

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with an etchant comprising a chlorine and a fluorine source, wherein the chlorine source can be CI2, and the fluorine source can be SF6 (col. 2, lines 9-24). Furthermore, Shoji discloses that this etchant provides an improved etching rate and selectivity between a refractory metal layer and SiO.

It is the Examiner's position that it would have been obvious to one of ordinary skill in the art at the time of the invention to modify Chen by further utilizing a fluorine source in the first etchant mixture, as per Shoji, in view of Shoji's disclosure about the benefits of such an etchant mixture.

In regard to claims 8 and 12-35, these claims differ from the claims discussed above by adding the further limitations of specific power ranges and concentrations. Although not disclosed by Chen or Shoji, it is the Examiner's position that the variation of result-effective process parameters, such as concentration and power, would have been obvious to one of ordinary skill in the art, if only for experimentation purposes, in order to determine the optimum process conditions.

Response to Arguments

- 6. Applicant's arguments with respect to claims 1-35 have been considered but are moot in view of the new ground(s) of rejection.
- 7. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Vanessa Perez-Ramos whose telephone number is 703-306-5510. The examiner can normally be reached on Mon-Thurs 7:00am-5:30pm.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Benjamin Utech can be reached on 703-308-3836. The fax phone numbers for the organization where this application or proceeding is assigned are 703-872-9310 for regular communications and 703-872-9311 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-306-5665.

Vanessa Perez-Ramos Examiner

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VPR March 9, 2003

> ROBERT KUNEMUND PRIMARY EXAMINER